

深圳市晶科鑫实业有限公司



样品承认书

客户代码:	
物料名称:	贴片钟振
规格型号:	SMD3225 OSC 低抖动100fs 156.250MHz 3.3V -40~85℃ HCSL
P N/ SJK:	3ND156250D33HC
环保属性:	☒ RoHS ☒ REACH ☒ HF ☐ PAHS ☐ 其它
版 次:	A1 2026-5-10 初版
湿敏等级:	一级

承 认 签 章					
供 应 商 承 认			() 公 司 承 认		
制 定	审 核	核 准	工 程 师	审 核	批 准
贺丹斌	李相同	刘惠光			
SJK 支持			盖章签署		
FAE_EMAIL			日 期		
日 期					
备注：					

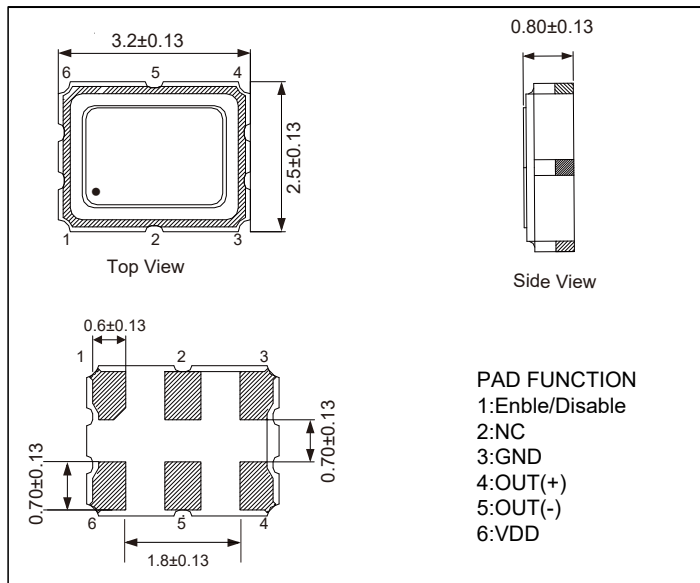
ELECTRICAL SPECIFICATIONS

Parmeters	Condition\Model	3NJD
Fan Out Type 输出模式		HCSL
Supply Voltage 供电电压		3.3V±10%
Frequency 频率		156.250MHz
Operating Temperature 工作温度		-40℃ to +85℃
Current 工作电流		40mA Max
Frequency Stability 频率稳定度	All Conditions	±50ppm
Output Voltage 输出电压	Vol 低电平	-0.15V Min-0.15V Max
	VoH 高电平	0.6V Min-0.9V Max
Rise/Fall Time 上升 / 下降时间	20%~80%	6.0ns Max
Load 负载		50Ω
Duty Cycle 占空比		50±5%
Storge Temperature 存储温度		-55~+125℃
Output Voltage Swing 输出电压摆幅		500mV Min 950mV Max
Start-upTime 启动时间		10ms Max
Aging 年老化率		±3ppm (first year at 25℃)
RMS Jitter 相位抖动	(12kHz to 20MHz)	100 fs
Input Voltage 输入电压	VIH 高电平	0.7 VDD Min
	VIL 低电平	0.3 VDD Max

Crystal oscillator SMD LVDS Output 3.2×2.5mm 3NJD Series



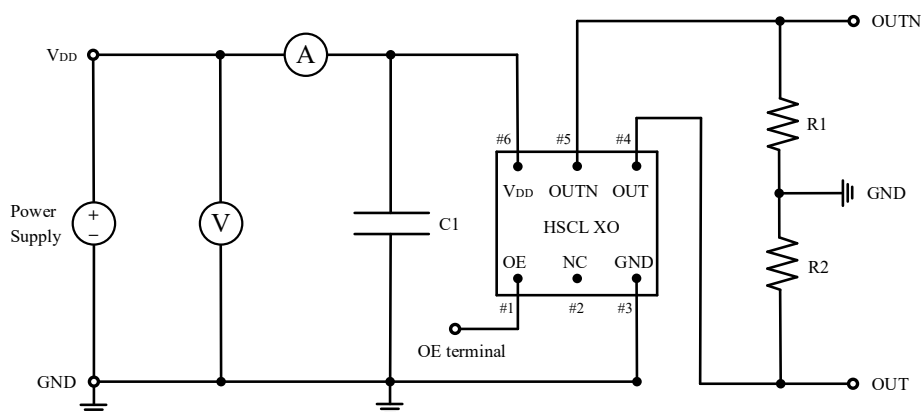
DIMENSION (Unit: mm)



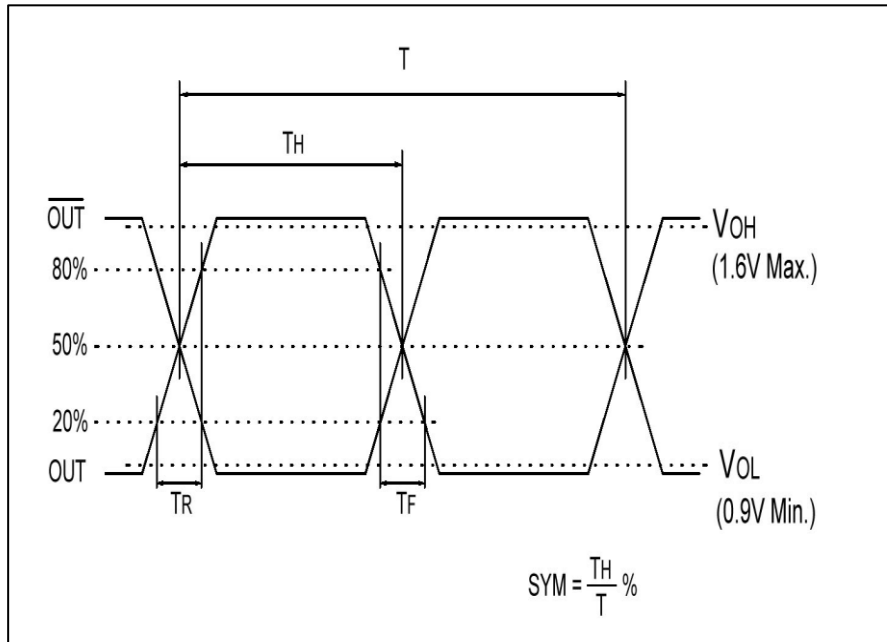
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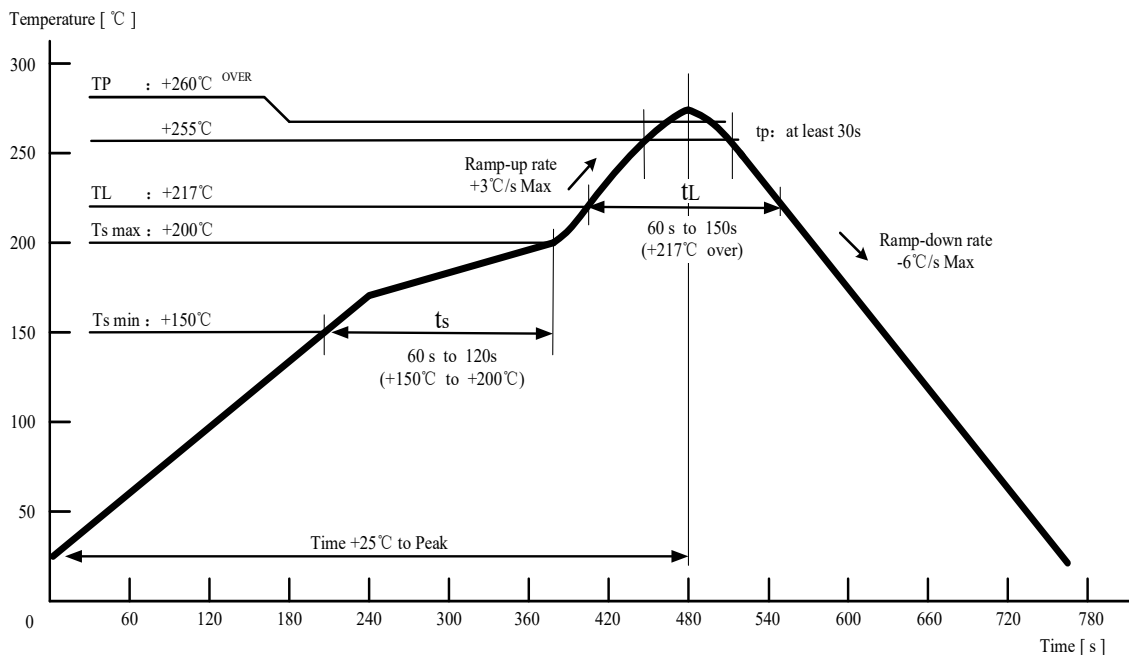
MEASUREMENT CIRCUIT



WAVEFORM CONDITIONS

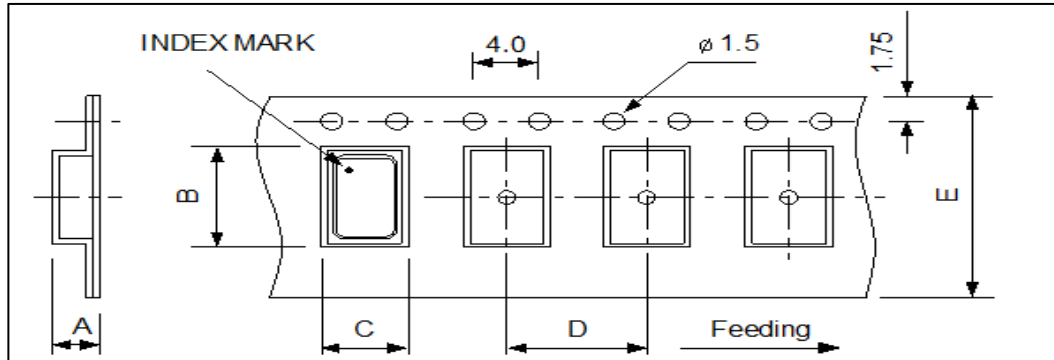


REFLOW CONDITION

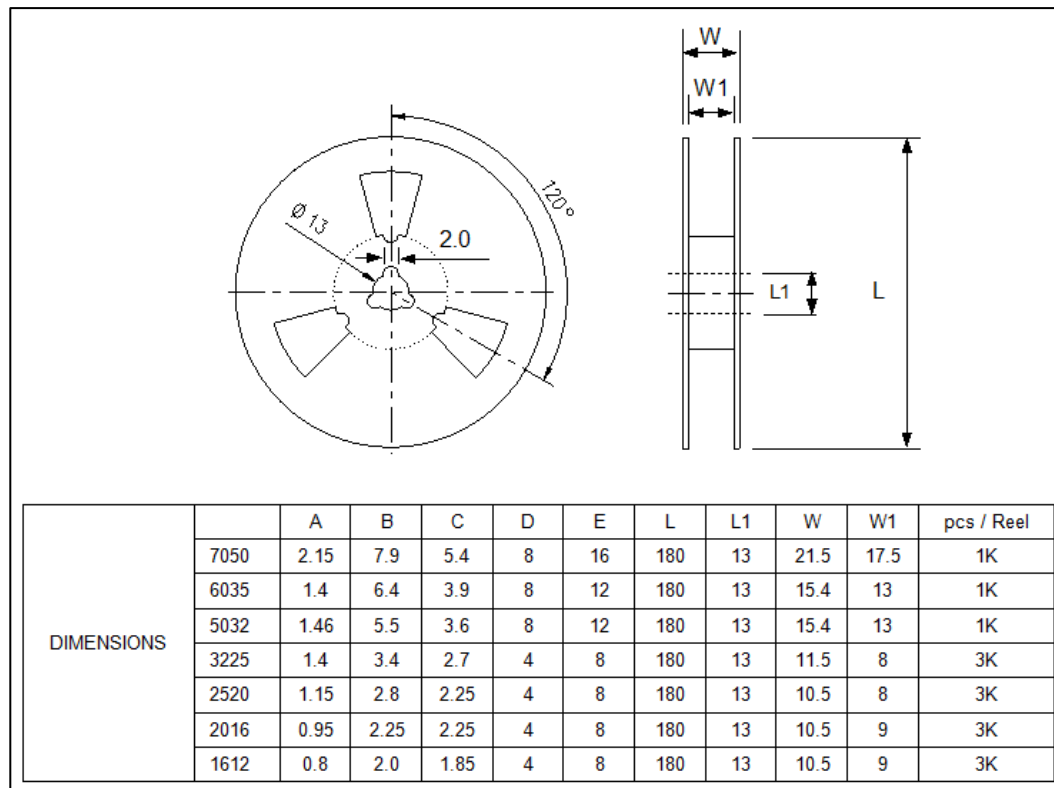


The reflow temperature profile may vary depending on the product model, specifications and frequency range. Refer to the individual product specifications for details

CARRIER TYPE



REEL



RELIABILITY TEST SPECIFICATIONS

Test item	Equipment	Condition	Specification
1.SOLDERABILITY TEST	SJK-REL001、RC-328A	TP:260℃ TsMax: 200℃ TsMin: 150℃ 2 time 	MIL-STD-883E Method 2003.7
2. HERMETICITY TEST	HELIOT-306S	Pressurized 0.4~0.5Mpa ethanol sealed tank for 10 minutes	MIL-STD-883E Method 1014.10
3. VIBRATION TEST	HG-V4、S&A 250B	Enable Crystal(10g) from 10-55-10Hz,X、Y、Z horizontal,1 Minute vibration/time, 1time/ 2 hours.	MIL-STD-883E Method 2007.3
4. MECHANICAL SHOCK	HPC-200、S&A 250B	Enable Crystal 50G(490m/s ²) time=11 ms speed=3.4 m/s half sine wave oscillation	JIS C6701
5. DROP TEST	HARD BOARD.S&A250B	75cm High,3 times on hard board	MIL-STD-202F Method 213B
6. HIGH&LOW TEMP STORAGE TEST(Static test)	H-PTH-80CK & HM101-3ABN, S&A 350B/250B	High temperature: 125℃±2℃,1000hr; Low temperature:-40℃±3℃,1000hrs	MIL-STD883C, METHOD 1011.8
7. TEMP & HUM CYCLING TEST	H-PTH-80CK CHAMBE, S&A 350B/250B	Temperature:-10℃±2℃~65℃±2℃,Humidity:93±3%,1 cycle need 24 hrs. 5cycles.	MIL-STD-883E Method 1005.8
8. HIGH TEM. & HUM.STORAGE TEST	H-PTH-80CK CHAMBE, S&A350B/250B	Temperature:85℃±2, Humidity:85+3,-2%,Store 96 hrs	JIS C6701
9. AGING TEST	H-PTH-80CK CHAMBE, S&A350B/250	Temperature:85℃±2, Store 1000 hrs	JIS C5023